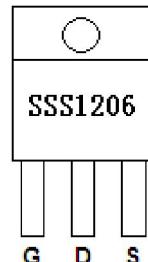


## Main Product Characteristics

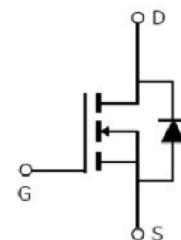
$V_{DSS}$	120V
$R_{DS(on)}$	4mΩ (typ.)
$I_D$	180A ①



TO-220



Marking and Pin Assignment



Schematic Diagram

## Features and Benefits

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature
- Lead free product



## Description

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

## Absolute Max Rating

Symbol	Parameter	Max.	Units
$I_D$ @ $T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	180 ①	A
$I_D$ @ $T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	130 ①	
$I_{DM}$	Pulsed Drain Current ②	670	
$P_D$ @ $T_C = 25^\circ C$	Power Dissipation ③	375	W
	Linear Derating Factor	2.5	W/ $^\circ C$
$V_{DS}$	Drain-Source Voltage	120	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy @ $L=0.3mH$	1045	mJ
$I_{AS}$	Avalanche Current @ $L=0.3mH$	83.5	A
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +175	$^\circ C$

## Thermal Resistance

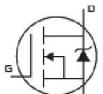
Symbol	Characteristics	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	0.4	°C/W
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10s$ ) ④	—	62	°C/W
	Junction-to-Ambient (PCB mounted, steady-state) ④	—	40	°C/W

**Electrical Characteristics** @ $T_A=25^\circ C$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	120	—	—	V	$V_{GS} = 0V, I_D = 1mA$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	4.0	6.0	mΩ	$V_{GS}=10V, I_D = 75A$
		—	9.0	—		$T_J = 125^\circ C$
$V_{GS(th)}$	Gate threshold voltage	2.0	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
		—	2.2	—		$T_J = 125^\circ C$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	μA	$V_{DS} = 120V, V_{GS} = 0V$
		—	—	50		$T_J = 125^\circ C$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20V$
		—	—	-100		$V_{GS} = -20V$
$Q_g$	Total gate charge	—	224	—	nC	$I_D = 50A,$ $V_{DS}=50V,$ $V_{GS} = 10V$
$Q_{gs}$	Gate-to-Source charge	—	80	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	55	—		
$t_{d(on)}$	Turn-on delay time	—	40	—	nS	$V_{GS}=10V, V_{DD} = 65V,$ $R_L=0.87\Omega,$ $R_{GEN}=2.6\Omega$ $I_D = 75A$
$t_r$	Rise time	—	141	—		
$t_{d(off)}$	Turn-Off delay time	—	95	—		
$t_f$	Fall time	—	101	—		
$C_{iss}$	Input capacitance	—	5634	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output capacitance	—	657	—		$V_{DS} = 50V$
$C_{rss}$	Reverse transfer capacitance	—	12.6	—		$f = 1MHz$

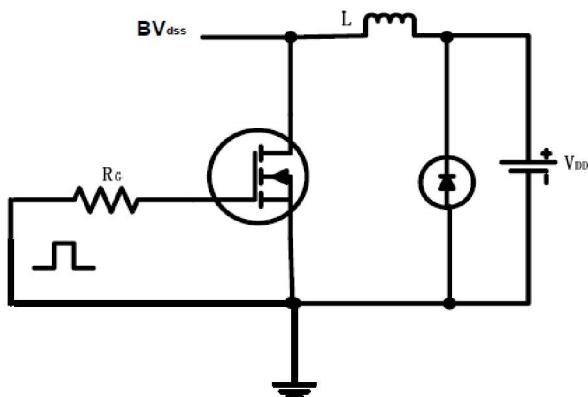
## Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	180 ①	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	670	A	
$V_{SD}$	Diode Forward Voltage	—	0.9	1.3	V	$I_s=75A, V_{GS}=0V, T_J = 25^\circ C$

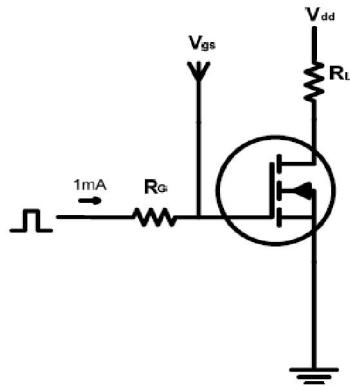


## Test Circuits and Waveforms

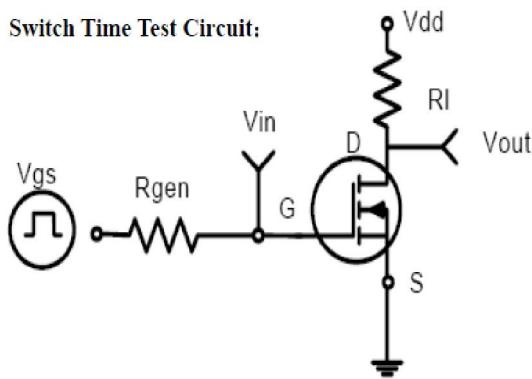
EAS test circuits:



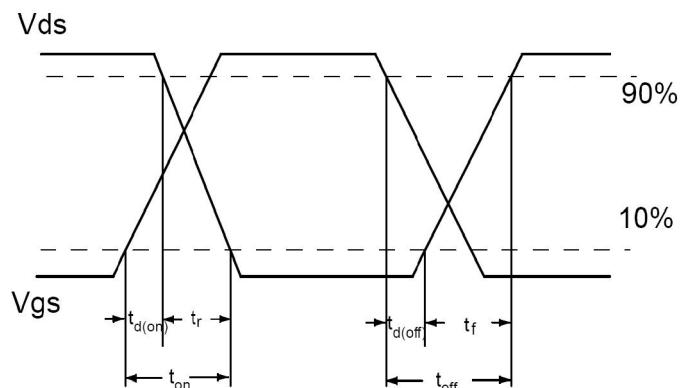
Gate charge test circuit:



Switch Time Test Circuit:



Switch Waveforms:



## Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $TA = 25^{\circ}\text{C}$

### Typical Electrical and Thermal Characteristics

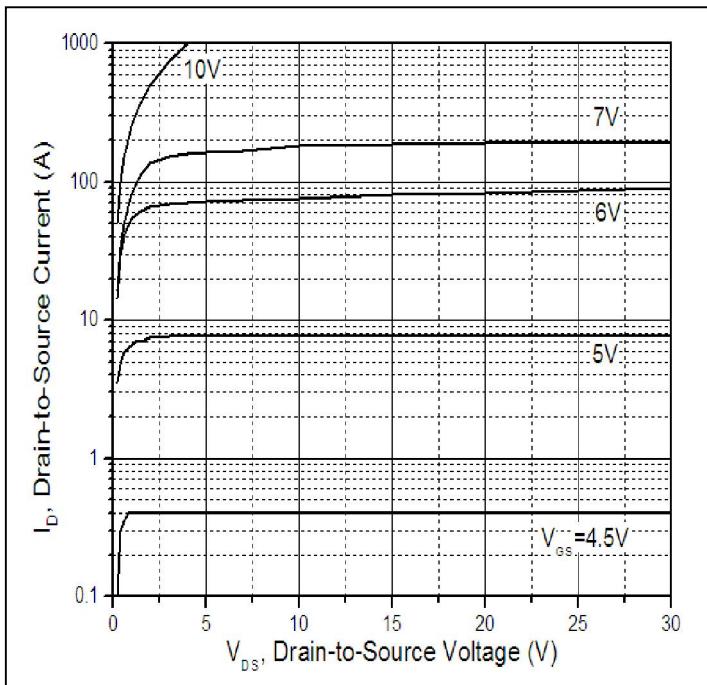


Figure 1: Typical Output Characteristics

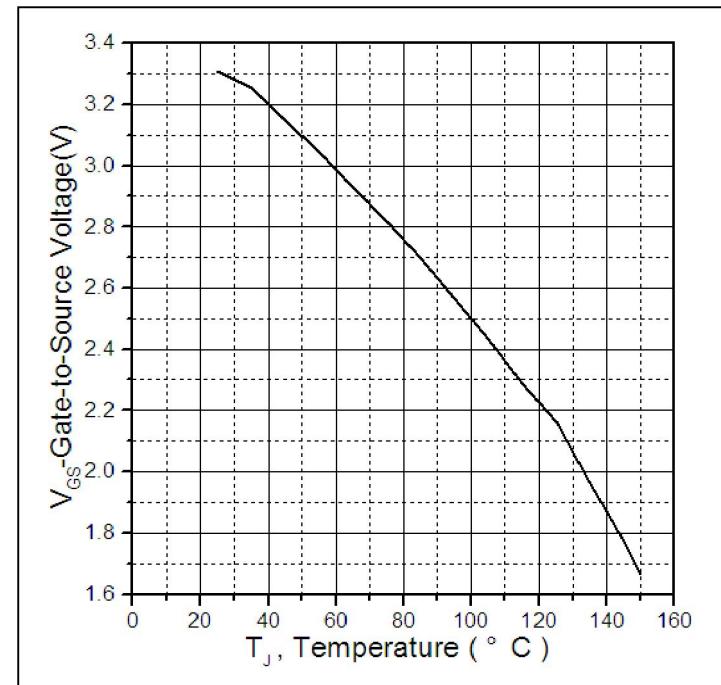


Figure 2. Gate to source cut-off voltage

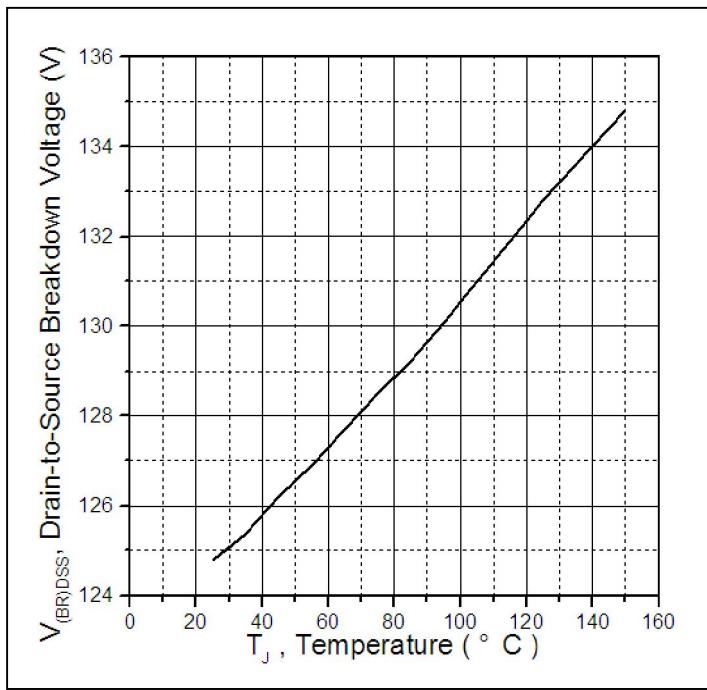


Figure 3. Drain-to-Source Breakdown Voltage Vs.  
Case Temperature

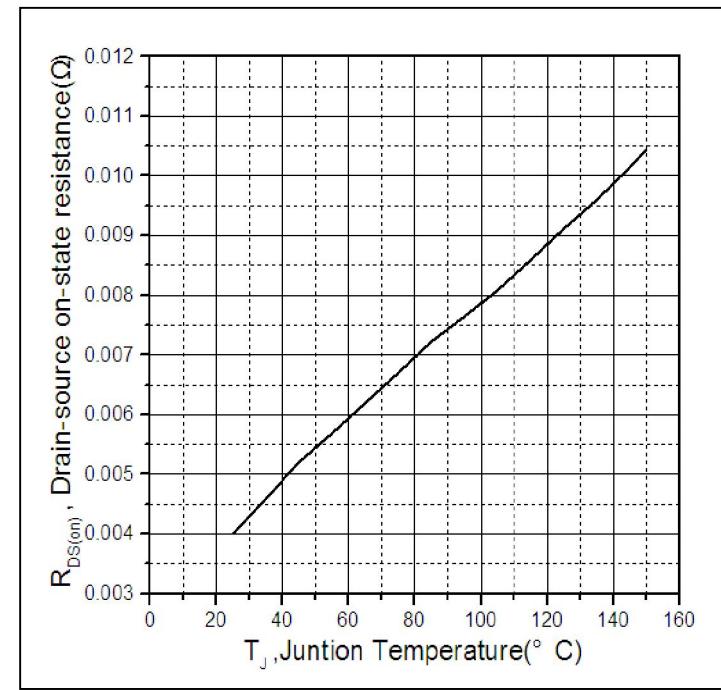
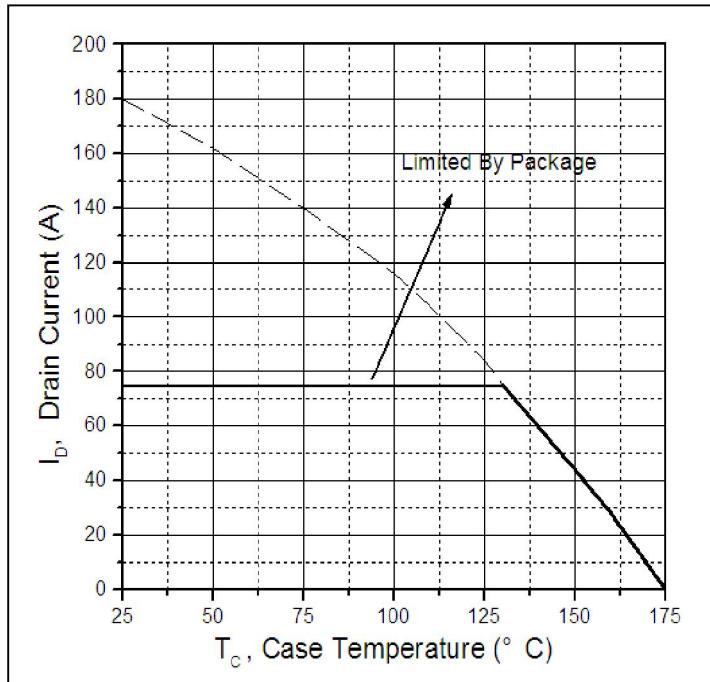
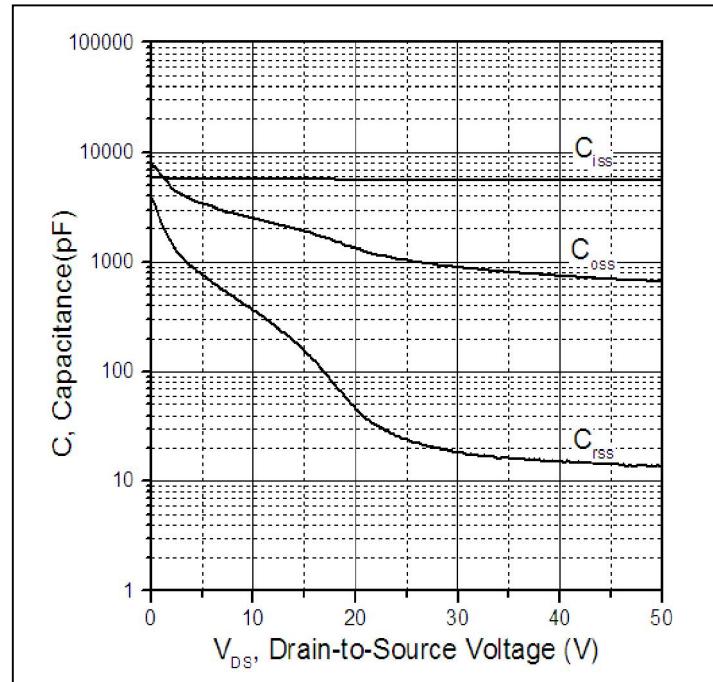


Figure 4: Normalized On-Resistance Vs. Case  
Temperature

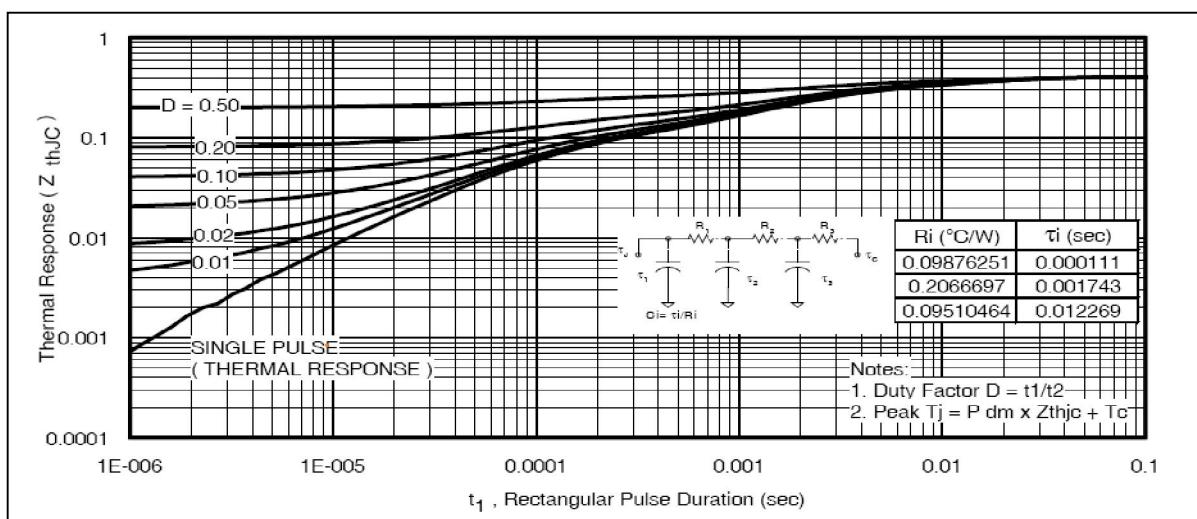
## Typical Electrical and Thermal Characteristics



**Figure 5. Maximum Drain Current Vs. Case Temperature**



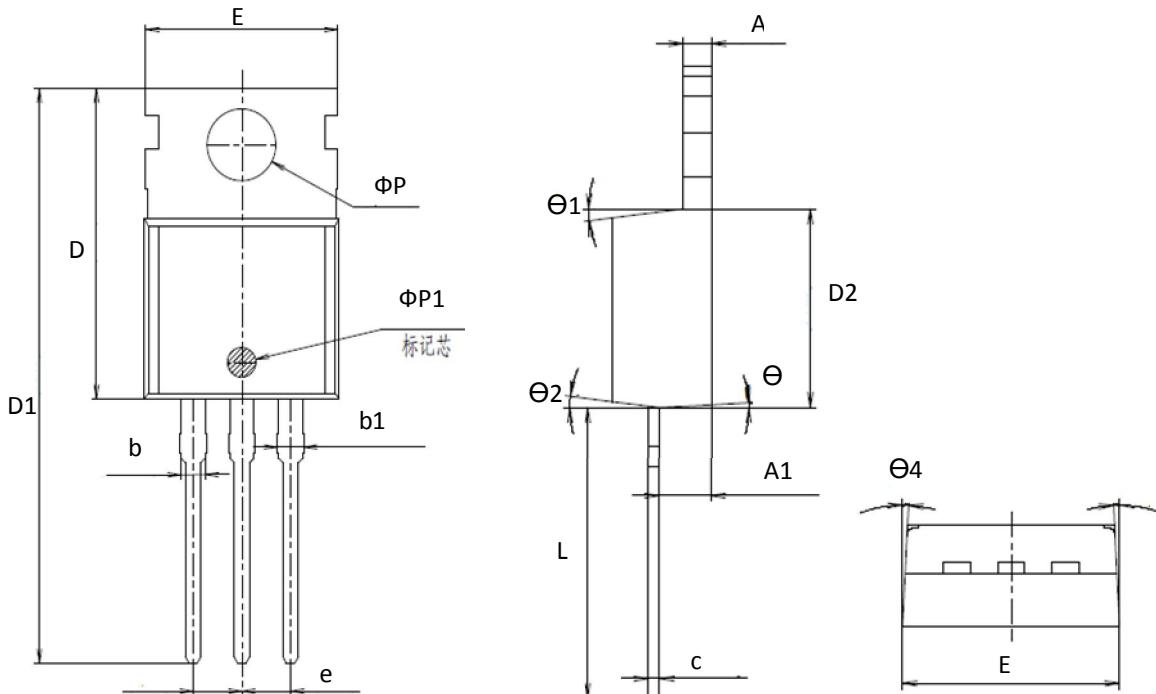
**Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage**



**Figure7. Maximum Effective Transient Thermal Impedance, Junction-to-Case**

## Mechanical Data

TO-220 PACKAGE OUTLINE DIMENSION\_GN



Symbol	Dimension In Millimeters			Dimension In Inches		
	Min	Nom	Max	Min	Nom	Max
A	-	1.300	-	-	0.051	-
A1	2.200	2.400	2.600	0.087	0.094	0.102
b	-	1.270	-	-	0.050	-
b1	1.270	1.370	1.470	0.050	0.054	0.058
c	-	0.500	-	-	0.020	-
D	-	15.600	-	-	0.614	-
D1	-	28.700	-	-	1.130	-
D2	-	9.150	-	-	0.360	-
E	9.900	10.000	10.100	0.390	0.394	0.398
E1	-	10.160	-	-	0.400	-
ΦP	-	3.600	-	-	0.142	-
ΦP1		1.500			0.059	
e	2.54BSC			0.1BSC		
L	12.900	13.100	13.300	0.508	0.516	0.524
Θ1	-	7°	-	-	7°	-
Θ2	-	7°	-	-	7°	-
Θ3	-	3°	-	5°	7°	9°
Θ4	-	3°	-	1°	3°	5°



## Ordering and Marking Information

### Device Marking: SSS1206

Package (Available)

TO-220

Operating Temperature Range

C : -55 to 175 °C

### Devices per Unit

Package Type	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO220	50	20	1000	6	6000

### Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	$T_j=125^\circ\text{C}$ to $175^\circ\text{C}$ @ 80% of Max $V_{DSS}/V_{CES}/VR$	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	$T_j=125^\circ\text{C}$ or $175^\circ\text{C}$ @ 100% of Max $V_{GSS}$	168 hours 500 hours 1000 hours	3 lots x 77 devices